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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Susie X. YANG et al.

Serial No. 10/809,908

Group Art Unit: 2125

Filed: March 26, 2004

Examiner: Ryan A. Jarrett

For:

IMPROVED CONTROL OF METAL RESISTANCE IN SEMICONDUCTOR

PRODUCTS VIA INTEGRATED METROLOGY

REPLY TO OFFICE ACTION

Honorable Commissioner for Patents Alexandria, VA 22313-1450

Sir:

This submission is responsive to the Office Action dated June 28, 2005. A petition for a two-month extension of time accompanies this reply to extend the period for response up to and including November 28, 2005.

Amendments to the claims are found starting on page 2 of this paper.

Remarks/Arguments start on page 14 of this paper.